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Applicatio	n/Control No.	Applicant(s). Reexaminati	/Patent under on
09/963,34	4	BRUNK ET	AL.
Examiner		Art Unit	
Tom Y. Lu	l	2621	

SEARCHED				
Class	Subclass	Date	Examiner	
382	100, 162- 167	6/10/2005	TYL	
358	2.1, 452	6/10/2005	TYL	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
382	100	6/10/2005	TYL
358	2.1, 452	6/10/2005	TYL
382	162-167	6/10/2005	TYL

SEARCH NO (INCLUDING SEARCE		)
	DATE	EXMR
EAST search printout attached	6/10/2005	TYL
SPIE search printout attached	6/10/2005	TYL
IEEE search printout attached	6/10/2005	TYL
PALM inventor name search	6/10/2005	TYL
consulted with primary examiner Andrew Johns	6/10/2005	TYL